Titles of Most Frequently Occurring Classifications of Patents Returned
From A Search of 10630537 on November 16, 2005

26   714/726   (19 OR, 7 XR)
        Class   714 : ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
        714/699   PULSE OR DATA ERROR HANDLING
        714/724   .Digital logic testing
        714/726   ..Scan path testing (e.g., level sensitive scan
                            design (LSSD))

12   714/727   (6 OR, 6 XR)
        Class   714 : ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
        714/699   PULSE OR DATA ERROR HANDLING
        714/724   .Digital logic testing
        714/726   ..Scan path testing (e.g., level sensitive scan
                            design (LSSD))
        714/727   ...Boundary scan

10   714/30   (7 OR, 3 XR)
        Class   714 : ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
        714/100   DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

        714/1   .Reliability and availability
        714/25   ..Fault locating (i.e., diagnosis or testing)

        714/27   ...Particular access structure
        714/30   ....Built-in hardware for diagnosing or testing
                            within-system component (e.g., microprocessor test mode
                            circuit, scan path)

 6   714/724   (3 OR, 3 XR)
        Class   714 : ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
        714/699   PULSE OR DATA ERROR HANDLING
        714/724   .Digital logic testing

 6   714/729   (1 OR, 5 XR)
        Class   714 : ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
        714/699   PULSE OR DATA ERROR HANDLING
        714/724   .Digital logic testing
        714/726   ..Scan path testing (e.g., level sensitive scan
                            design (LSSD))
        714/729   ...Plural scan paths

 5   324/158.1   (1 OR, 4 XR)
        Class   324 : ELECTRICITY: MEASURING AND TESTING
        324/158.1   MISCELLANEOUS

 5   365/201   (0 OR, 5 XR)
        Class   365 : STATIC INFORMATION STORAGE AND RETRIEVAL
        365/189.01   READ/WRITE CIRCUIT
        365/201   .Testing

 5   714/733   (0 OR, 5 XR)
        Class   714 : ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
        714/699   PULSE OR DATA ERROR HANDLING
        714/724   .Digital logic testing

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        714/733        ..Built-in testing circuit (BILBO)

4   714/731        (2 OR, 2 XR)
        Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
        714/699        PULSE OR DATA ERROR HANDLING
        714/724        .Digital logic testing
        714/726        ..Scan path testing (e.g., level sensitive scan
                          design (LSSD))
        714/731        ...Clock or synchronization

4   716/4          (0 OR, 4 XR)
        Class   716 :  DATA PROCESSING:  DESIGN AND ANALYSIS OF
                          CIRCUIT OR SEMICONDUCTOR MASK
        716/1          CIRCUIT DESIGN
        716/4          .Testing or evaluating

3   324/73.1       (0 OR, 3 XR)
        Class   324 :  ELECTRICITY:  MEASURING AND TESTING
        324/73.1       PLURAL, AUTOMATICALLY SEQUENTIAL TESTS

3   714/732        (1 OR, 2 XR)
        Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
        714/699        PULSE OR DATA ERROR HANDLING
        714/724        .Digital logic testing
        714/732        ..Signature analysis

2   714/33         (1 OR, 1 XR)
        Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
        714/100        DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

        714/1          .Reliability and availability
        714/25         ..Fault locating (i.e., diagnosis or testing)

        714/32         ...Particular stimulus creation
        714/33         ....Derived from analysis (e.g., of a
                          specification or by stimulation)

2   714/718        (2 OR, 0 XR)
        Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
        714/699        PULSE OR DATA ERROR HANDLING
        714/718        .Memory testing

2   714/725        (0 OR, 2 XR)
        Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
        714/699        PULSE OR DATA ERROR HANDLING
        714/724        .Digital logic testing
        714/725        ..Programmable logic array (PLA) testing

2   714/734        (0 OR, 2 XR)
        Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
        714/699        PULSE OR DATA ERROR HANDLING
        714/724        .Digital logic testing
        714/734        ..Structural (in-circuit test)

2   714/736        (0 OR, 2 XR)
        Class   714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
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